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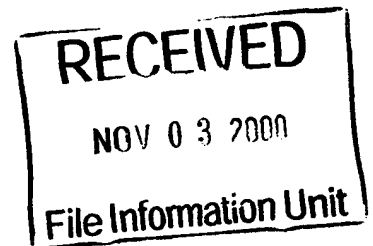
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FOR : APPARATUS AND METHOD FOR DETECTING MICRO  
DEFECTS IN SEMI-CONDUCTORS

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Sir:

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Respectfully submitted,

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